

Technical Data KT 638-3

Test points						
Type of test point cards	RM60	RM80	RM100 / RM16	RM120		
Max. number of test point cards	8					
Max. number of test points	512					
Test point interface	Female connector DIN 41612, 64-way		Female connector DIN 41612, 32-way			
General						
Power supply	100 – 240 VAC (50 - 60 Hz)					
Dimensions (W x H x D)	450 mm x 150 mm x 395 mm					
Weight	approx. 8 kg					
Environmental conditions	Temperature range: operation: +10 °C – +40 °C storage: +10 °C – +60 °C					
	Relative humidity: 20 % – 70 %, non-condensing					
Operating	Operating unit consisting of a high-contrast LC-display with 4 x 20 characters and 11 keys					
	Operating languages: German, English, French, Italian, Spanish, Danish, Czech, Polish, Hungarian and Japanese (further languages on request)					
Features	Self-learning of known good samples Programming with test program editor NT Control LT (PC software) Elaborate possibilities for the output and formatting of test results for printer and/or file Expanded label and report printing, also to file Test procedure control for the customization to special test tasks Division of the test procedure into single test steps (segments) e.g. for the test of switch positions or for segment specific parameters Visual check of LEDs					
Diagnosis	Self-diagnosis for the measurement electronics and the test point cards					
Interfaces	Network Serial interface (RS232) / 3 x USB 2.0 (1 x front, 2 x rear) 3 x I/O, digital, 24 V, D-Sub 15-way Interface for warning lamp red-green, foot switch, test result lamp Pin number probe for test point identification Safety loop for the protection of the work place RJ12 interface for the connection of a temperature and humidity sensor					
Specialties	Microsoft® Network Client and server software pre-installed and configured					
Data storage	Flash Memory 2 GB internal and USB flash drive ≥ 2 GB					
Scope of delivery	KT 638, main cable, pin number probe, USB flash drive with NT Control LT and documentation in PDF format					

Options	
	Test program selection via I/O card
	Checking and testing with barcode
	Correction value determination for R, C, L and Z
	Digital I/O interfaces 24 V, 8, 16 or 24 I/Os, D-Sub 37-way
	Test system remote control via digital I/Os, serial interface or all common field-bus systems
	Temperature and humidity protocol, 0 - 100 % rF $\pm 2\%$, -40 - 80 °C ± 0.3 K
	LCR measuring bridge
	Adapter cables as well as I/O connection cables and I/O interface boards
	Interface for adaptronic test tables
	Installation set 19"
	UNICAD converter for CAD- and Excel link data

Measurement electronics MT20

Low voltage test	
Test voltage	1 – 25 V programmable in steps of 1 V ($\pm 3\%$, min. 0.2 V)
Test current	max. 25 mA
Threshold continuity test	1 Ohm – 1 kOhm ($\pm 5\%$, min. 1 Ohm)
Threshold short-circuit test	20 kOhm – 1 MOhm ($\pm 5\%$) Option: up to 5 MOhm ($\pm 20\%$ at test voltages ≥ 20 V)

Component test	
Resistors	1 Ohm – 1 MOhm ($\pm 5\%$, min. 1 Ohm) Option: up to 5 MOhm ($\pm 20\%$ at test voltages ≥ 20 V)
Capacitors	10 nF – 20 mF ($\pm 10\%$) Option: from 100 pF ($\pm 10\%$, ± 20 pF)
Diodes	Forward voltage: < 1.0 V Reverse voltage: max. 25 V
Zener diodes	Forward voltage: < 3.0 V Zener voltage: max. 20 V ($\pm 10\%$)
LEDs	Forward-Voltage: < 4.0 V Reverse voltage: max. 25 V
Suppressor diode	Break-down voltage: 3 V – 23 V ($\pm 10\%$)

Measurement electronics MT1500DC

High voltage test													
Test voltage	RM60 / RM100 / RM16	40 – 1000 VDC ($\pm 2\%$); in steps of 1 V											
	RM80 / RM120	40 – 1500 VDC ($\pm 2\%$); in steps of 1 V											
Test current	max. 2 mA (safety current limited according to EN 61010)												
Testing times	Rise time 0 – 60000 ms; in steps of 10 ms Dwell time 0 – 60000 ms; in steps of 10 ms												
Insulation test	500 kOhm – 2 GOhm Option: up to 10 GOhm (not valid for Distributed Test Systems or unearthing operation) in steps of 500 kOhm												
Dielectric strength test	Fast recognitions of voltage breakdowns at test voltages ≥ 200 V (arc detections)												
Accuracy in dependence of the voltage:													
Voltage	500 kOhm – 500 MOhm	> 500 MOhm – 2 GOhm	> 2 GOhm – 10 GOhm										
1500 V	2 %	5 %	15 %										
≥ 1000 V	2 %	5 %	$\geq 15\%$										
≥ 500 V	2 %	$\geq 15\%$	$\geq 15\%$										
	500 kOhm – 100 MOhm	> 100 MOhm – 2 GOhm	> 2 GOhm – 10 GOhm										
≥ 100 V	2 %	$\geq 15\%$	$\geq 15\%$										
High current test													
Test current	50 mA – 2 A (1 A with RM16); in steps of 10 mA												
Test voltage	max. 22 VDC												
Test times	Dwell time 0 – 60000 ms; in steps of 100 ms												
Threshold continuity test	500 mOhm – 10 Ohm, $\pm 2\%$, min. 200 mOhm 10 Ohm – 1 kOhm, $\pm 5\%$ (dwell time ≥ 100 ms) in steps of 500 mOhm												
	1 mOhm – 1000 Ohm; in steps of 1 mOhm $\pm 2\%$, min. 1 mOhm at test current ≥ 1 A $\pm 5\%$, min. 5 mOhm at test current < 1 A, min. 50 mOhm												
Four-wire measurement 1 mOhm (option)	<table border="1"> <thead> <tr> <th>Resolution</th><th>Measuring range</th></tr> </thead> <tbody> <tr> <td>13 μOhm</td><td>at 2 A test current: 100 μOhm – 50 mOhm</td></tr> <tr> <td>245 μOhm</td><td>at 2 A test current: 50 mOhm – 1 Ohm</td></tr> <tr> <td>4,9 mOhm</td><td>at 2 A test current: 1 Ohm – 11 Ohm</td></tr> <tr> <td>0.045 % of measured value</td><td>if test current of 2 A is not reached due to voltage limitation: 11 Ohm – 1000 Ohm</td></tr> </tbody> </table> <p>Note: The measuring ranges change depending on the specified test current.</p>			Resolution	Measuring range	13 μ Ohm	at 2 A test current: 100 μ Ohm – 50 mOhm	245 μ Ohm	at 2 A test current: 50 mOhm – 1 Ohm	4,9 mOhm	at 2 A test current: 1 Ohm – 11 Ohm	0.045 % of measured value	if test current of 2 A is not reached due to voltage limitation: 11 Ohm – 1000 Ohm
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Four-wire measurement 100 μ Ohm (option)	<p>100 μOhm – 1000 Ohm; minimum step size 100 μOhm</p> <p>Measuring range 100 μOhm – 1 mOhm: Measurement accuracy absolute $\pm 20\%$ at test current 2 A Repeating accuracy $\pm 10 \mu$Ohm Measuring time min. 4.8 s</p> <p>Measuring range 1 mOhm – 1000 Ohm: $\pm 2\%$, min. 1 mOhm at test current ≥ 1 A $\pm 5\%$, min. 5 mOhm at test current < 1 A, min. 50 mOhm</p> <table border="1"> <thead> <tr> <th>Resolution</th><th>Measuring range</th></tr> </thead> <tbody> <tr> <td>1 μOhm</td><td>at 2 A test current: 100 μOhm – 50 mOhm</td></tr> <tr> <td>16 μOhm</td><td>at 2 A test current: 50 mOhm – 1 Ohm</td></tr> <tr> <td>305 μOhm</td><td>at 2 A test current: 1 Ohm – 11 Ohm</td></tr> <tr> <td>0.0028 % of measured value</td><td>if test current of 2 A is not reached due to voltage limitation: 11 Ohm – 1000 Ohm</td></tr> </tbody> </table> <p>Note: The measuring ranges change depending on the specified test current.</p>			Resolution	Measuring range	1 μ Ohm	at 2 A test current: 100 μ Ohm – 50 mOhm	16 μ Ohm	at 2 A test current: 50 mOhm – 1 Ohm	305 μ Ohm	at 2 A test current: 1 Ohm – 11 Ohm	0.0028 % of measured value	if test current of 2 A is not reached due to voltage limitation: 11 Ohm – 1000 Ohm
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Not suitable for unearthing operation.													

Short time interruptions AMC (option)	Interruptions $\geq 1 \mu\text{s}$			
Component test				
Varistors				
Varistor voltage	RM60 / RM100 / RM16	40 – 900 VDC		
	RM80 / RM120	40 – 1300 VDC		
Test current	1 mA			
Surge arrestors				
Breakdown voltage	RM60 / RM100 / RM16	100 – 900 VDC		
	RM80 / RM120	100 – 1300 VDC		
Ramp	100 V/s or 1000 V/s			

Conditions for all tolerance statements: operating mode „Precise Mode“, earthbound operation, environmental conditions 15 – 35 °C / 20 – 60 % rel. humidity (non-condensing)

The statements for the component test refer to the test of single components, which are connected separately with test points.

Technical data and tolerances are subject to change depending on a specific ambient of the test object or application.